

Search Notes

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Examiner

John D. Lee

Applicant(s)/Patent under
Reexamination

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Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
359	326-332	7/27/2005	JDL
359	107,108	7/27/2005	JDL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
359	326-332	7/27/2005	JDL
359	107,108	7/27/2005	JDL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Previous USPTO "WEST" Database search updated (same search terms)	7/27/2005	JDL